



**NOTICE**

**Sub: Selection Procedure**

**Name of the Post: Technical Superintendent - Electrical (PL 6; Group B)**

**Ref: Advt. No. IITGoa/RECT/2024/02 dated 04.10.2024**

**1. Selection Will Be Based Performance in Written Test.**

**2. Pattern of the Written Test:**

- The Written Test will be conducted in Two Stages, i.e. Written Test I and Written II. Candidates securing minimum qualifying marks as laid down by the selection committee in Written Test I shall be shortlisted for Written test II. The final selection will be based on aggregate marks obtained from both the Written Tests (I & II) with weightage of 40% in Written Test I and 60% in Written Test II.
- Written Test I will Consist of 50 Multiple Choice Questions of 1 Marks Each. 0.25 Negative Marks for every wrong answer. Duration of the Test is 90 minutes.
- Written Test II will be a Trade Test of 50 marks

**3. Syllabus:**

**Circuit Analysis:** Node and Mesh Analysis, Superposition, Thevenin's Theorem, Norton's Theorem, Reciprocity. Sinusoidal Steady State Analysis: Phasors, Complex Power, Maximum Power Transfer. Time and Frequency Domain Analysis of Linear Circuits: RL, RC and RLC Circuits, Solution of Network Equations Using Laplace Transform. Linear 2-Port Network Parameters, Wye-Delta Transformation.

**Analog Circuits:** Diode Circuits - Clipping, Clamping and Rectifiers. BJT and MOSFET Amplifiers - Biasing, AC Coupling, Small Signal Analysis, Frequency Response, Channel Length Modulation. Current Mirrors and Differential Amplifiers. Op-Amp Circuits: Amplifiers, Summers, Differentiators, Integrators, Active Filters, Schmitt Triggers and Oscillators. Feedback Topologies.

**Digital Circuits:** Number Representations - Binary, Integer and Floating-Point- Numbers, Combinatorial Circuits - Boolean Algebra, Minimization of Functions Using Boolean Identities and Karnaugh Map, Logic Gates and Their Static CMOS Implementations, Arithmetic Circuits, Code Converters, Multiplexers, Decoders. Sequential Circuits - Latches and Flip-Flops, Counters, Shift-Registers, Finite State Machines, Propagation Delay, Setup and Hold Time, Critical Path Delay. Data Converters - Sample and Hold Circuits, ADCS and DACS. Semiconductor Memories - ROM, SRAM, DRAM. Computer Organization - Machine Instructions and Addressing Modes, ALU, Data-Path and Control Unit, Instruction Pipelining. Microprocessors and Microcontrollers.

**Power Electronics:** Static V-I Characteristics And Firing/Gating Circuits For Thyristor, MOSFET, IGBT; DC To DC Conversion: Buck, Boost And Buck-Boost Converters; Single And Three-Phase Configuration Of Uncontrolled Rectifiers; Thyristor Based Converters; Bidirectional AC To DC Voltage Source Converters; Magnitude And Phase Of Line Current Harmonics For Uncontrolled And Thyristor Based Converters; Power Factor And Distortion Factor Of AC To DC Converters; Singlephase And Three-Phase Voltage Source Inverters, Sinusoidal Pulse Width Modulation.

**4. Date of Written Test: Friday, 07/03/2025 at IIT Goa Campus 10:00 AM onwards**

**Sd/-  
Registrar**